

<b>Notice of References Cited</b>	Application/Control No. 10/562,327		Applicant(s)/Patent Under Reexamination TAKENAKA ET AL.	
	Examiner JONATHAN SAMPLE		Art Unit 4184	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0009259	01-2003	Hattori et al.	700/245
*	B	US-6,289,265	09-2001	Takenaka et al.	700/245
*	C	US-5,644,204	07-1997	Nagle, John	318/568.12
*	D	US-6,021,363	02-2000	Nishikawa et al.	700/253
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U				
	V				
	W				
	X				

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.